

Search Notes

Application/Control No.

10/533,440

Examiner

Chris H. Chu

Applicant(s)/Patent under
Reexamination

ROSMAN ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
applicants' cited references	2/23/2006	CC
text search	2/23/2006	CC
IEEE database	2/24/2006	CC